

Due: Wednesday, April 30, 2003

1. For an n-channel Si MOSFET with an oxide thickness $d=150 \text{ \AA}$, a channel mobility $\mu_n = 1000 \text{ cm}^2/\text{V-s}$, $Z=100 \text{ }\mu\text{m}$, and $L=5 \text{ }\mu\text{m}$, determine the threshold voltages for $N_a = 10^{15}$ and $10^{17}/\text{cm}^3$, respectively. Calculate and tabulate $I_D(V_D, V_G)$ in the linear region at 300 K. Allow V_D to take on values of 0.1, 0.3, 0.5, 0.7, 0.9 and 1.1 V for $V_G = 2, 3, 4$, and 5 V. Assume that $Q_i = 5 \times 10^{11} \text{ qC/cm}^2$. Also, determine $I_{D\text{sat}}$ in the saturation region for each gate bias and doping.
2. Plot I_D vs. V_D for $V_G = -2, -3$, and -4V for a thin-oxide (100\AA) p-channel transistor. The substrate doping and effective interface charge are $N_d=10^{16} \text{ cm}^3$ and $Q_i = 5 \times 10^{10} \text{ q C/cm}^2$, respectively. Assume that $I_{D\text{sat}}$ remains constant beyond pinch-off and $\mu_p=200 \text{ cm}^2/\text{V-s}$ and $Z=10L$.